

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18

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Title of Invention

INCREASE PRODUCTIVITY AT WAFER TEST USING PROBE
RETEST DATA ANALYSIS

Application Number :

Confirmation Number:

First Named Applicant: Akiko Balchiunas

Attorney Docket Number: BUR920040137US1

Art Unit:

Examiner:

Search string: (6240329 or 6350959 or 6507800 or 6618682 or 20030120445 or 20030139839
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US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	6240329	2001-05-29	Sun			
	2	6350959	2002-02-26	Beffa			
	3	6507800	2003-01-14	Sheu			
	4	6618682	2003-08-09	Bulaga et al.			

US Published Applications

Note: Applicant is not required to submit a paper copy of cited US Published Applications

init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
	1	20030120445	2003-06-26	Barbour et al.			
	2	20030139839	2003-07-24	Beffa			

Signature

Examiner Name	Date